

	Type	Hits	Search Text	DBs	Time Stamp	Comments
1	BRS	2	improv\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
2	BRS	2	improv\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
3	BRS	18	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:47	
4	BRS	1	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with processing with system\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:01	

Type	Hits	Search Text	DBs	Time Stamp	Comments
5 BRS	3	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
6 BRS	8	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
7 BRS	0	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and (calculat\$3 or comput\$3) with error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
8	BRS	5	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and (calculat\$3 or comput\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:29	
9	BRS	3	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:30	
10	BRS	3	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
11	BRS	4	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	
12	BRS	4	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and accurac\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:32	
13	BRS	21	tim\$3 with edge\$1 same accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:45	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
14	BRS	13	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:51	
15	BRS	9	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	
16	BRS	10	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
17	BRS	1	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:53	
18	BRS	12	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
19	BRS	4	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and instruct\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
20	BRS	5	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
21	BRS	12	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
22	BRS	15	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
23	BRS	0	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:05	
24	BRS	4	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
25	BRS	4	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	
26	BRS	4	(calibrat\$3 or adjust\$3) with tim\$3 with edg\$3 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:08	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
27	BRS	28	(calibrat\$3 or adjust\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:08	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
			(calibrat\$3 or adjust\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3 and computer\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:09	
28	BRS	20				
29	BRS	9747	702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:10	
30	BRS	2	improv\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
31	BRS	2	improv\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
32	BRS	19	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:49	
33	BRS	2	(expected or desired) with tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:49	
34	BRS	2	"20060036387"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:58	
35	BRS	1	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with processing with system\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:01	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
36	BRS	3	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
37	BRS	8	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
38	BRS	0	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and (calculat\$3 or comput\$3) with error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:11	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
39	BRS	2	(compar\$4 or differen\$2) with tim\$3 with edge\$1 with signal\$1 with (threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) and (DUT or device\$1 adj. under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and (calculat\$3 or comput\$3) with error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:15	
40	BRS	1	tim\$3 with edge\$1 with signal\$1 with (threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) same (DUT or device\$1 adj under adj test) with (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:17	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
41	BRS	26	tim\$3 with edge\$1 with signal\$1 with (threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) same (DUT or device\$1 adj under adj test) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:20	
42	BRS	1	tim\$3 with occurrence\$1 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:21	
43	BRS	8	(threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) with tim\$3 with point\$1 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:26	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
44	BRS	39	(threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) with tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:27	
45	BRS	2	(determin\$3 or calculat\$3 or computing or comput or computa) with (threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) with tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:27	
46	BRS	5	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and (calculat\$3 or comput\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:29	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
47	BRS	3	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:30	
48	BRS	3	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	
49	BRS	4	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
50	BRS	4	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and accurac\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:32	
51	BRS	23	tim\$3 with edge\$1 same accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:46	
52	BRS	40	tim\$3 with edge\$1 same occurs\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:49	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
53	BRS	24	tim\$3 with edge\$1 with occur\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	
54	BRS	0	compar\$4 with tim\$3 with edge\$1 with occur\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	
55	BRS	4	compar\$4 same tim\$3 with edge\$1 with occur\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
56	BRS	14	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:51	
57	BRS	10	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	
58	BRS	11	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
59	BRS	2	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:58	
60	BRS	2	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:59	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
61	BRS	13	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
62	BRS	5	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and instruct\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
63	BRS	13	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
64	BRS	5	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and instruct\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
65	BRS	6	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
66	BRS	6	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
67	BRS	13	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
68	BRS	13	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
69	BRS	17	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	
70	BRS	0	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
71	BRS	5	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	
72	BRS	5	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
73	BRS	5	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edg\$3 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:08	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
74	BRS	32	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:09	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
75	BRS	24	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3 and computer\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:09	
76	BRS	18	(702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:18	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
77	BRS	6	(702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:13	
78	BRS	2	(702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:13	
79	BRS	112	tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:17	
80	BRS	23	(702/57,69,117.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:24	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
81	BRS	86	("702"/\$.ccls. or "714"/\$.ccls. or "324"/\$.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:19	
82	BRS	42	(702/57,69,117,119.ccls. or 714/700,718,724,736,742,74 3,744,815.ccls. or 324/158.1.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:25	
83	BRS	243	(702/57,69,117,119.ccls. or 714/700,718,724,736,742,74 3,744,815.ccls. or 324/158.1.ccls.) and tim\$3 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:31	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
84	BRS	116	(702/57, 69, 117, 119.ccls. or 714/700, 718, 724, 736, 742, 74 3, 744, 815.ccls. or 324/158.1.ccls.) and tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:25	
85	BRS	53	(702/57, 69, 117, 119.ccls. or 714/700, 718, 724, 736, 742, 74 3, 744, 815.ccls. or 324/158.1.ccls.) and tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:27	
86	BRS	9	(702/57, 69, 117, 119.ccls. or 714/700, 718, 724, 736, 742, 74 3, 744, 815.ccls. or 324/158.1.ccls.) and tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 11:29	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
87	BRS	12	(count\$3 or occur\$6 or number\$1) with tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 12:28	
88	BRS	4	(compa\$4 or differen\$2) with (count\$3 or occur\$6 or number\$1) with tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 11:30	
89	BRS	43	(702/57, 69, 117, 119.ccls. or 714/700, 718, 724, 736, 742, 743, 744, 815.ccls. or 324/158.1.ccls.) and tim\$3 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 11:31	
90	BRS	170	cycle\$ with signal\$1 with tester\$1 with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:46	
91	BRS	70	generat\$3 with cycle\$ with signal\$1 with tester\$1 with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:47	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
92	BRS	6	generat\$3 with cycle\$ with edge with signal\$1 with tester\$1 with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:49	
93	BRS	7	generat\$3 with cycle\$ with edge with signal\$1 with ((DUT or device adj under adj test\$3) or tester\$1) with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:50	
94	BRS	12	(count\$3 or occur\$6 or number\$1) with tim\$3 with (peak\$1 or edge\$1) with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 12:28	
95	BRS	0	compar44 with expected with tim\$3 with edge with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 12:55	
96	BRS	40	compar\$4 with expected with tim\$3 with edge with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 12:55	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
97	BRS	2	compar\$4 with expected with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
98	BRS	2	compar\$4 with (desired or expected) with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
99	BRS	2	(differen\$2 or compar\$4) with (desired or expected) with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
100	BRS	10	(differen\$2 or compar\$4) with (desired or expected) with tim\$3 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:08	
101	BRS	126	tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:08	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
102	BRS	14	(adjust\$3 or calibrat\$3 or compensat\$3) with tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:14	
103	BRS	0	(adjust\$3 or calibrat\$3 or compensat\$3) with tim\$3 with edge\$1 with signal\$1 with actual same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:15	
104	BRS	0	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with ((expected or desired) adj tim\$3) same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:16	
105	BRS	0	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with (expected or desired) same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:16	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
106	BRS	1	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with (expected or desired) and (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:17	
107	BRS	6	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with (expected or desired or predefined or predetermined or preset\$4 or reference\$1 or threshold\$1) and (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:21	
108	BRS	12	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (expected or desired or predefined or predetermined or preset\$4 or reference\$1 or threshold\$1) with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:23	

Type	Hits	Search Text	DBs	Time Stamp	Comments
109 BRS	9	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (expected or desired or predefined or predetermined or preset\$4 or reference\$1 or threshold\$1) with tim\$3 with edge\$1 and cycle\$1 with tim\$3 and (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 14:31	
110 BRS	3	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (tester\$1 or DUT or device\$1 adj under adj test\$3)) with cycle\$1 with time\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 14:33	

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
1			US 2006004982 0 A1	20060309	17	Method and apparatus for remotely buffering test channels	324/158.1		324/158.1
2	X		US 2006003172 8 A1	20060209	15	Method and apparatus for measuring digital timing paths by setting a scan mode of sequential storage elements	714/724		714/724
3	X		US 2006001035 8 A1	20060112	21	Method and apparatus for calibrating and/or deskewing communications channels	714/700	455/67.16	714/700
4	X		US 2005026769 6 A1	20051201		Measurement instrument and measurement method	702/57		702/57
5	X		US 2005024660 3 A1	20051103	12	Pin coupler for an integrated circuit tester	714/742		714/742
6	X		US 2005024660 1 A1	20051103		Method and apparatus to measure and display data dependent eye diagrams	714/724		714/724

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
7	X		US 2005022531 4 A1	20051013		Method of measuring duty cycle	324/158.1		324/158.1
8	X		US 2005019335 5 A1	20050901	19	Source synchronous timing extraction, cyclization and sampling	716/6	703/19; 714/724	714/724
9	X		US 2005016033 1 A1	20050721		PICA system timing measurement and calibration	714/700		714/700
10	X	X	US 2005009742 0 A1	20050505	26	Apparatus for jitter testing an IC	714/742		714/742
11	X		US 2005008816 7 A1	20050428		Isolation buffers with controlled equal time delays	324/158.1		324/158.1
12	X		US 2005008058 0 A1	20050414	27	Device for testing lsi to be measured, jitter analyzer, and phase difference detector	702/117		702/117
13	X		US 2005005041 1 A1	20050303		Pre-stored digital word generator	714/724		714/724

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
14	X		US 2005003861 5 A1	20050217		Qualification signal measurement, trigger, and/or display system	702/69		702/69
15	X		US 2005003404 4 A1	20050210	25	Semiconductor test device and timing measurement method	714/742		714/742
16	X		US 2005002806 2 A1	20050203		Test method and apparatus for high-speed semiconductor memory devices	714/736		714/736
17	X		US 2005002208 8 A1	20050127		Semiconductor tester	714/744		714/744
18	X		US 2005002208 1 A1	20050127	42	Test systems and methods with compensation techniques	714/724		714/724
19	X		US 2005002208 0 A1	20050127	43	Systems and methods associated with test equipment	714/724		714/724
20	X		US 2004026049 2 A1	20041223	9	Direct jitter analysis of binary sampled data	702/69		702/69

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
21	X		US 2004015326 7 A1	20040805		System and method of testing a transceiver	702/69		702/69
22	X		US 2004012260 7 A1	20040624		System and method of measuring a signal propagation delay	702/69		702/69
23	X		US 2004007874 0 A1	20040422		Memory tester uses arbitrary dynamic mappings to serialize vectors into transmitted sub-vectors and de-serialize received sub-vectors into vectors	714/718		714/718
24	X		US 2004006476 5 A1	20040401		Deskewed differential detector employing analog-to-digital converter	714/700	714/724	714/700; 714/724
25	X		US 2004005151 8 A1	20040318		High speed tester with narrow output pulses	324/158.1		324/158.1
26	X		US 2004000332 8 A1	20040101		Instrument initiated communication for automatic test equipment	714/724		714/724

	U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
27	X		US 2003023360 4 A1	20031218		Memory device test system and method	714/718		714/718
28	X		US 2003022946 6 A1	20031211		Test method and apparatus for source synchronous signals	702/117		702/117
29	X		US 2003015868 7 A1	20030821	11	Composite eye diagrams	702/117		702/117
30	X		US 2003012653 0 A1	20030703	13	Time shift circuit for functional and AC parametric test	714/724		714/724
31	X		US 2003011712 9 A1	20030626	7	Low-cost tester interface module	324/158.1	324/765	324/158.1
32	X		US 2003011042 7 A1	20030612		Semiconductor test system storing pin calibration data in non-volatile memory	714/724		714/724
33	X	X	US 2003002883 2 A1	20030206	18	Driver for integrated circuit chip tester	714/700		714/700
34	X		US 2003000537 5 A1	20030102		Algorithmically programmable memory tester with test sites operating in a slave mode	714/724		714/724

	U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
35	X		US 2002018600 4 A1	20021212		Method for manufacturing smart card and identification devices and the like	324/158.1		324/158.1
36	X		US 2002018458 1 A1	20021205		Method for testing semiconductor chips and semiconductor device	714/724		714/724
37	X		US 2002017000 6 A1	20021114	17	Differential receiver architecture,	714/724		714/724
38	X		US 2002015243 7 A1	20021017	9	Circuitry for and system and substrate with circuitry for aligning output signals in massively parallel testers and other electronic devices	714/724		714/724
39	X	X	US 2002013535 7 A1	20020926	14	Method and apparatus for socket calibration of integrated circuit testers	324/158.1		324/158.1

	U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
40	X		US 2002012587 8 A1	20020912		High-frequency tester for semiconductor devices	324/158.1		324/158. 1
41	X		US 2002007776 3 A1	20020620		Automatic tester having separate coarse and precise timing modules	702/120	702/117	702/117
42	X		US 2002004289 8 A1	20020411		Test interface for verification of high speed embedded synchronous dynamic random access memory (SDRAM) circuitry	714/744	365/192	714/744
43	X		US 2001001046 2 A1	20010802		Carrier identification system, carrier identification method and storage media	324/158.1		324/158. 1